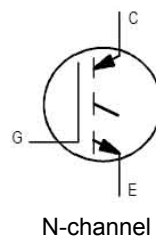


Features

- High short circuit rating optimized for motor control
- Low conduction losses
- High switching speed
- Tighter parameter distribution

$V_{CES} = 1200 \text{ V}$
 $V_{CE(on) \text{ typ.}} = 3,0 \text{ V}$
 $@V_{GE} = 15 \text{ V}, I_C = 40 \text{ A}$



ABSOLUTE MAXIMUM RATINGS

Parameter	Symbol	Units	Max
Collector-to-Emitter Voltage	V_{CES}	V	1200
Continuous Collector Current	$I_C @ T_C = 25^\circ\text{C}$	A	40
Continuous Collector Current	$I_C @ T_C = 100^\circ\text{C}$		20
Pulsed Collector Current ¹	I_{CM}		80
Clamped Inductive Load Current ²	I_{LM}		80
Short Circuit Withstand Time	tsc	μs	10
Maximum Power Dissipation	$P_D @ T_C = 25^\circ\text{C}$	W	180
Maximum Power Dissipation	$P_D @ T_C = 100^\circ\text{C}$		78
Gate-to-Emitter Voltage	V_{GE}	V	± 20
Operating Junction and Storage temperature Range	T_J T_{STG}	$^\circ\text{C}$	-55 to +150
Soldering Temperature, for 10 seconds		$^\circ\text{C}$	300

THERMAL RESISTANCE

Parameter	Symbol	Units	Min	Typ.	Max
Junction-to-Case	$R_{\theta JC}$	$^\circ\text{C/W}$	-	-	0,7
Case-to-Sink, Flat, Greased Surface	$R_{\theta CS}$		-	0,24	-
Junction-to-Ambient, typical socket mount	$R_{\theta JA}$		-	-	40

ELECTRICAL CHARACTERISTICS ($T_J = 25^\circ\text{C}$)

Parameter	Symbol	Units	Test Conditions	Min	Typ.	Max
Collector-to-Emitter Breakdown Voltage	$V_{(BR)CES}$	V	$V_{GE} = 0V, I_C = 250\mu A$	1200	-	-
Breakdown Voltage Temp.Coefficient	$\Delta V_{(BR)CES} / \Delta T_J$	V/ $^\circ\text{C}$	$V_{GE} = 0V, I_C = 2\text{ mA}$	-	0,9	-
Collector-to-Emitter Saturation Voltage	$V_{CE(ON)}$	V	$V_{GE} = 15V, I_C = 20A$	-	2,5	3,3
			$V_{GE} = 15V, I_C = 40A$	-	3,0	-
			$V_{GE} = 15V, I_C = 20A$ $T_J = 150^\circ\text{C}$	-	2,6	-
Gate Threshold Voltage	$V_{GE(th)}$	V	$V_{GE} = V_{CE}, I_C = 250\mu A$	3,0	-	6,0
Threshold Voltage Temp.Coefficient	$\Delta V_{(GE)th} / \Delta T_J$	mV/ $^\circ\text{C}$	$V_{GE} = V_{CE}, I_C = 2mA$	-	-10	-
Forward Transconductance	$g_{(fe)}$	S	$V_{CE} = 100V, I_C = 20\text{ A}$	12	18	-
Zero Gate Voltage Collector Current	I_{CES}	μA	$V_{CE} = 1200V, V_{GE} = 0V$	-	-	250
			$V_{CE} = 10V, V_{GE} = 0V$	-	-	2,0
			$V_{CE} = 1200V, V_{GE} = 0V$ $T_J = 150^\circ\text{C}$	-	-	5000
Gate-to-Emitter Leakage Current	I_{GES}	nA	$V_{GS} = \pm 20V$			± 100

SWITCHING CHARACTERISTICS ($T_J = 25^\circ\text{C}$)

Parameter	Symbol	Units	Test Conditions	Min	Typ.	Max
Total Gate Charge (turn on)	Q_g	nC	$V_{GE} = 15V, V_{CC} = 400V,$ $I_C = 20A$	-	168	256
Gate-to-Emitter Charge (turn on)	Q_{ge}			-	22	35
Gate-to-Collector Charge (turn on)	Q_{gc}			-	65	102
Turn-On Delay Time	$t_{d(on)}$	ns	$V_{CC} = 960V, I_C = 20A$ $V_{GE} = 15V, R_G = 24\Omega$	-	30	-
Rise Time	t_r			-	23	-
Turn-Off Delay Time	$t_{d(off)}$			-	180	270
Fall Time	t_f			-	120	178
Turn-On Switching Loss	E_{on}	mJ	Energy losses include «tail»	-	1,2	-
Turn-Off Switching Loss	E_{off}			-	2,1	-
Total Switching Loss	E_{TS}			-	3,2	4,0
Short Circuit Withstand Time	t_{sc}	μs	$V_{CC} = 720V, T_J = 125^\circ\text{C}$ $V_{GE} = 15V, R_G = 5,0\Omega$	10	-	-
Turn-On Delay Time	$t_{d(on)}$	ns	$T_J = 150^\circ\text{C}$ $V_{CC} = 960V, I_C = 24A$ $V_{GE} = 15V, R_G = 24\Omega$ Energy losses include «tail»	-	32	-
Rise Time	t_r			-	27	-
Turn-Off Delay Time	$t_{d(off)}$			-	370	-
Fall Time	t_f			-	267	-
Total Switching Loss	E_{TS}	mJ		-	7,70	-
Input Capacitance	C_{ISS}	pF	$V_{GE} = 0V, V_{CC} = 30V,$ $f = 1.0MHz$	-	2600	-
Output Capacitance	C_{OSS}			-	120	-
Reverse Transfer Capacitance	C_{RSS}			-	45	-

Notes:

¹ Repetitive rating; $V_{GE} = 20V$, pulse width limited by max junction temperature.

² $V_{CC} = 80\%(V_{CES})$, $L = 10\mu H$, $V_{GE} = 15V$, $R_G = 5,0\Omega$.

³ Pulse width $\leq 80\mu s$, duty factor $\leq 0,1\%$.

⁴ Pulse width $5,0\mu s$ single short.

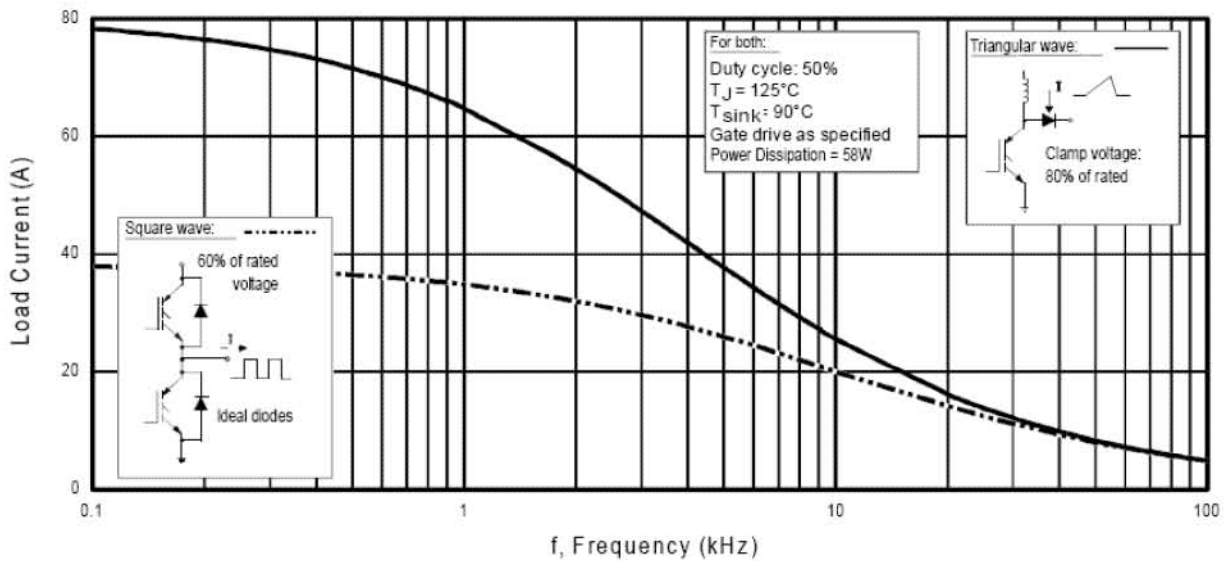


Fig.1 –Typical Load Current vs. Frequency
(For square wave, $I = I_{\text{RMS}}$ of fundamental; for triangular wave, $I = I_{\text{PK}}$)

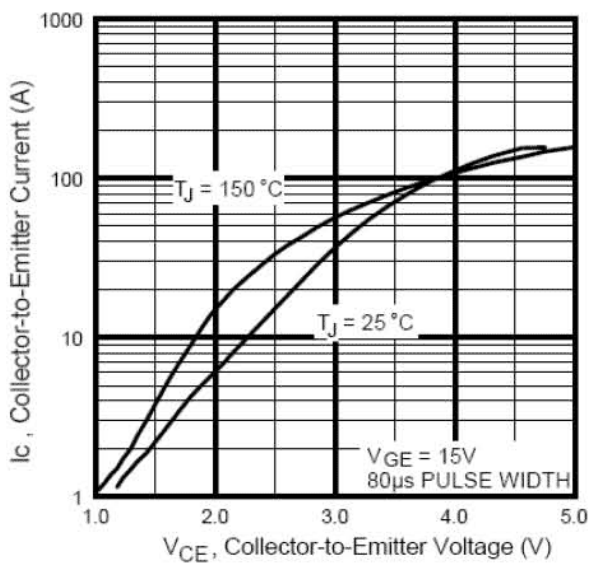


Fig.2 – Typical Output Characteristics

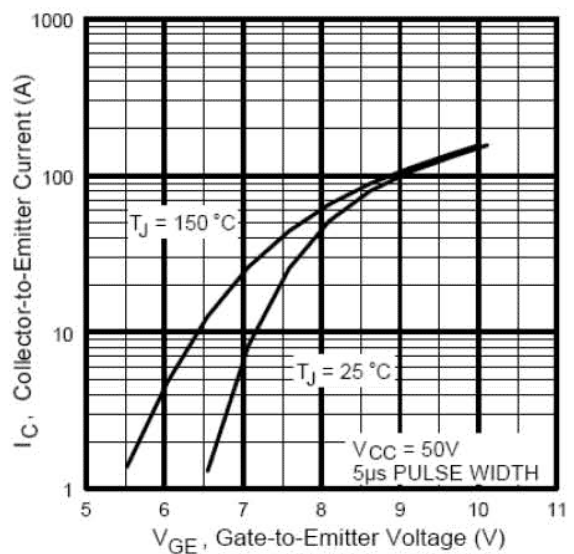


Fig.3 – Typical Transfer Characteristics

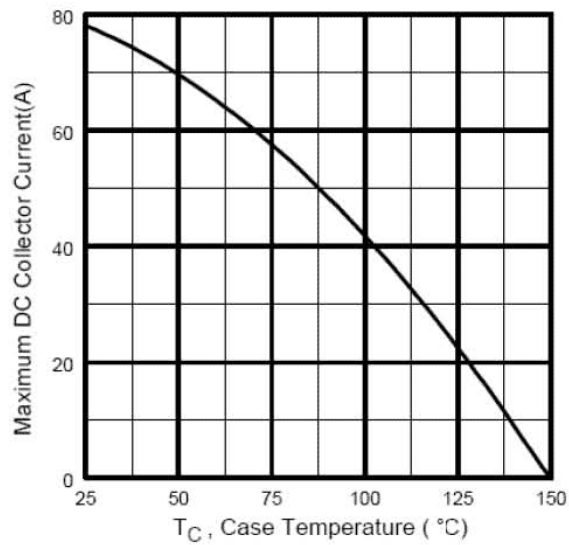


Fig.4 – Maximum Collector Current vs. Case Temperature

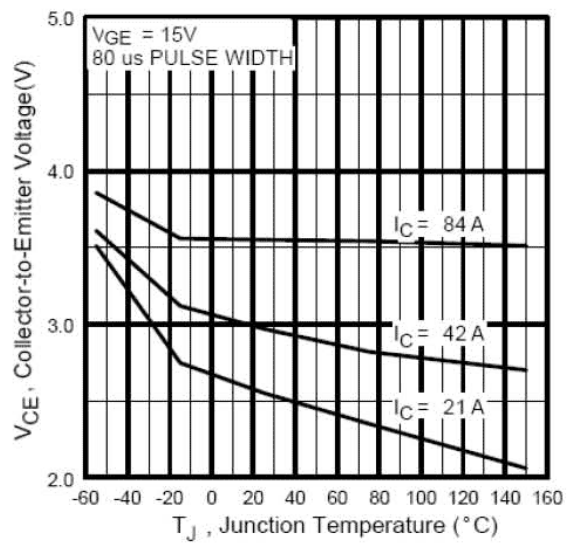


Fig.5 – Collector-to-Emitter Voltage VS. Junction Temperature

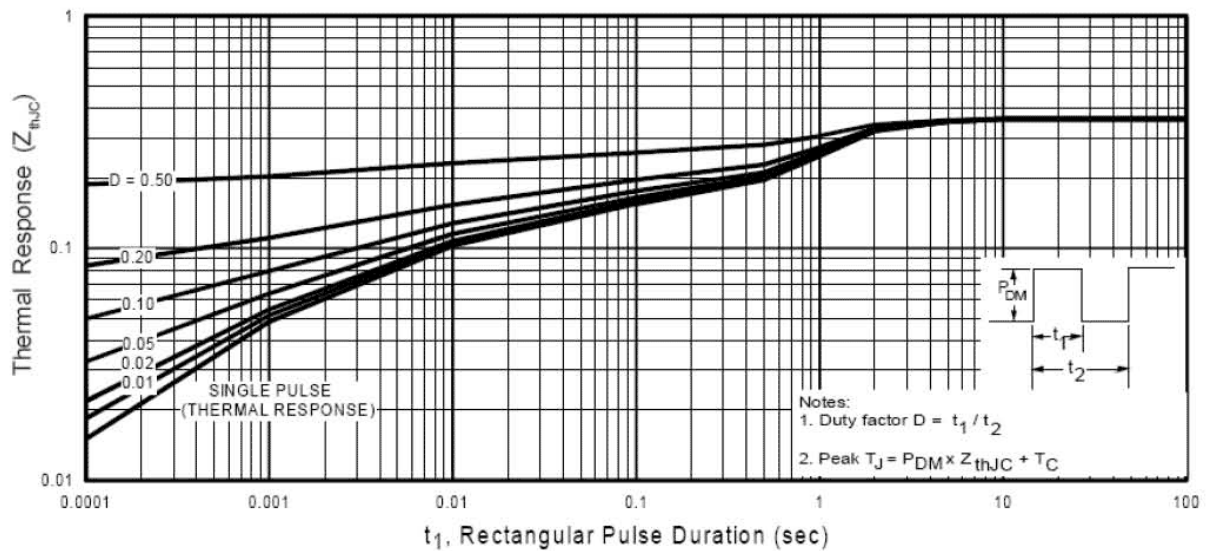
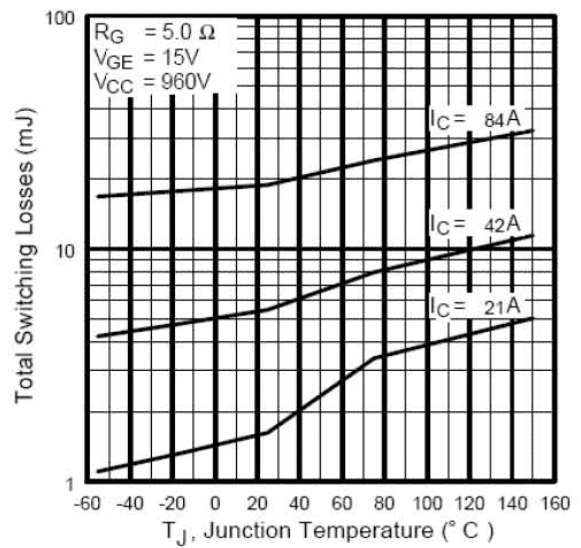
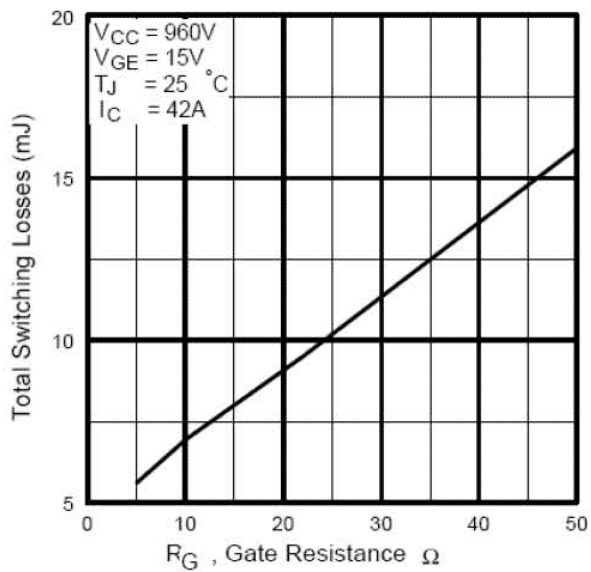
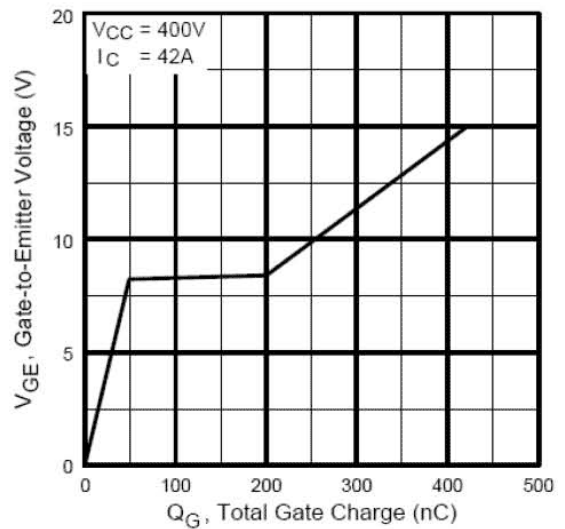
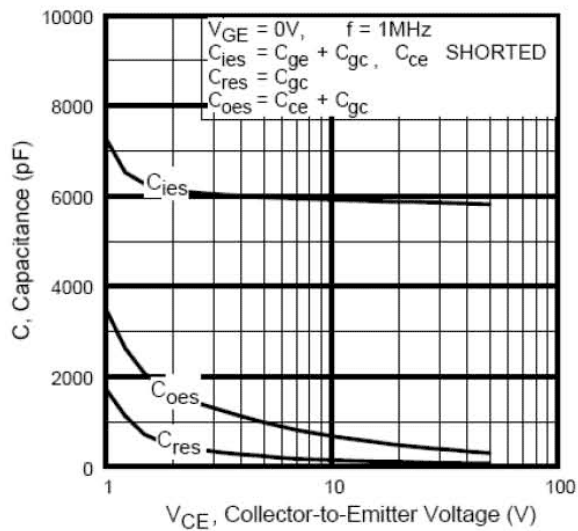


Fig.6 – Maximum Effective Transient Thermal Impedance, Junction-to-Case



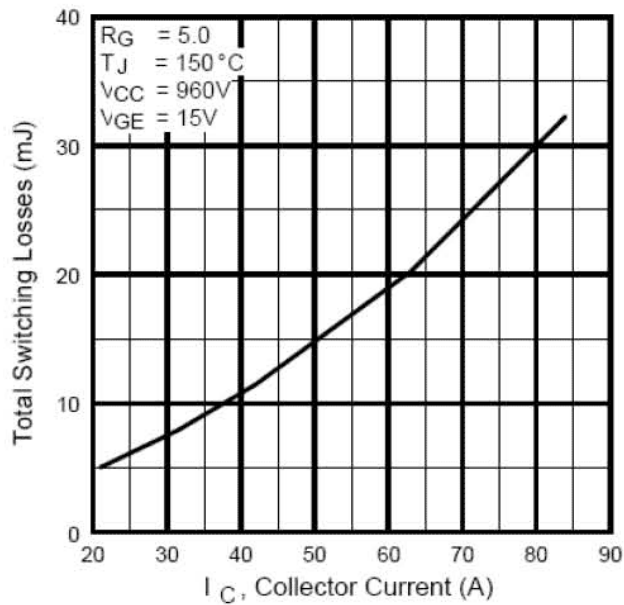


Fig. 11 – Typical Switching Losses vs. Collector-to-Emitter Current

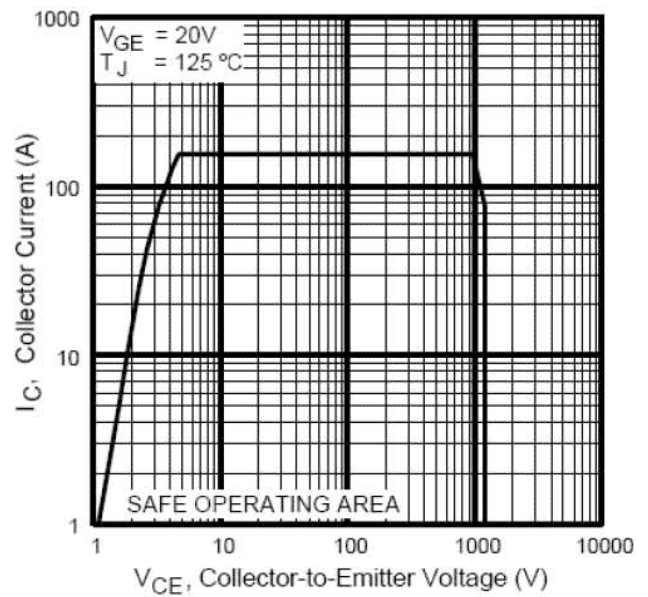
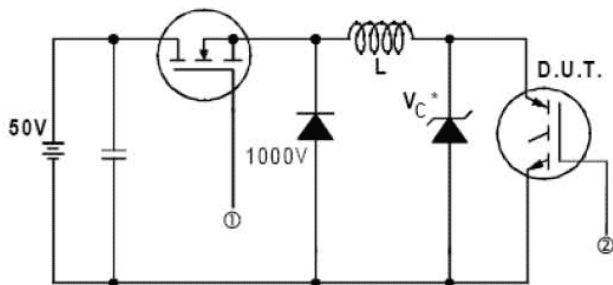


Fig.12-Turn-Off SOA



* Driver same type as D.U.T.; $V_c = 80\%$ of $V_{ce(max)}$
* Note: Due to the 50V power supply, pulse width and inductor will increase to obtain rated I_d .

Fig. 13a – Clamped Inductive Load Test Circuit

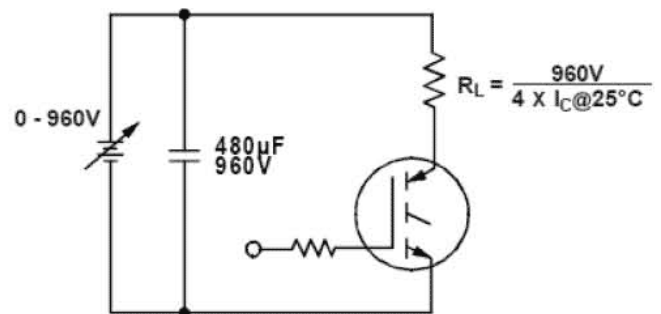


Fig. 13b – Pulsed Collector Current Test Circuit

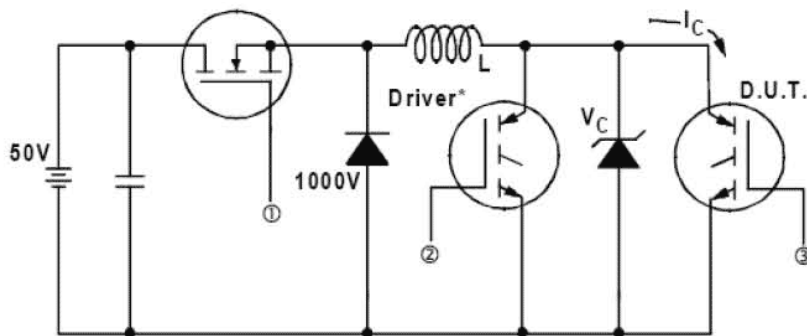


Fig. 14a - Switching Loss Test Circuit

* Driver same type as D.U.T., $V_c = 960V$

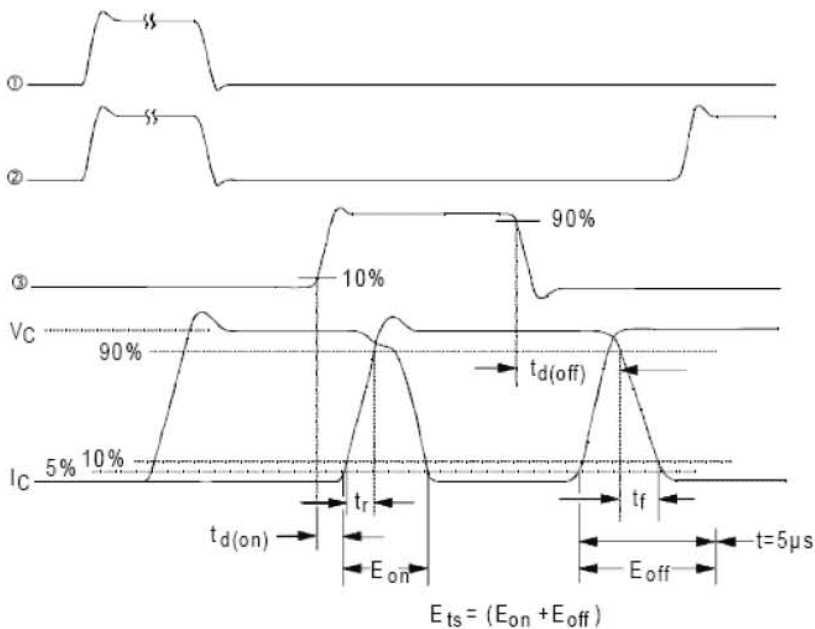


Fig. 14b - Switching Loss Waveforms